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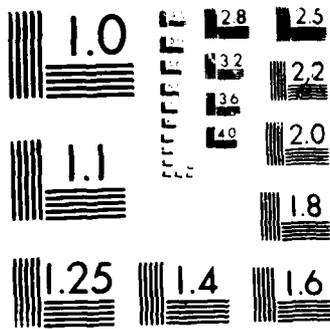
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ABSTRACT

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- Wang, L.T., and E.J. McCluskey, "Complete Feedback Shift Register Design for Built-In Self-Test," *ICCAD'86*, 11/11/86.

LIST OF ABBREVIATIONS

ICCAD'86 = International Conference on Computer-Aided Design, Santa Clara, CA, Nov. 10-13, 1986.

ISCAS'86 = Proceedings of the International Symposium on Circuits and Systems, San Jose, CA, May 5-7, 1986.

FJCC = Proceedings of the Fall Joint Computer Conference, Dallas, TX, Nov. 2-4, 1986.

ISSCC'86 = Proceedings of the IEEE International Symposium on Circuits and Systems, Anaheim, CA, Feb. 19-21, 1986.

COMPCON'86 = Computer Society International Conference, San Francisco, CA, March 3, 1986.

ITC'86 = International Test Conference, Washington, D.C., Sept. 8-11, 1986.

CICC = Custom Integrated Circuits Conference, Rochester, NY, May 12-15, 1986.

1986 SCHOLARS VISITING CRC

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Prof. Takashi Nanya, Tokyo Institute of Technology.

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